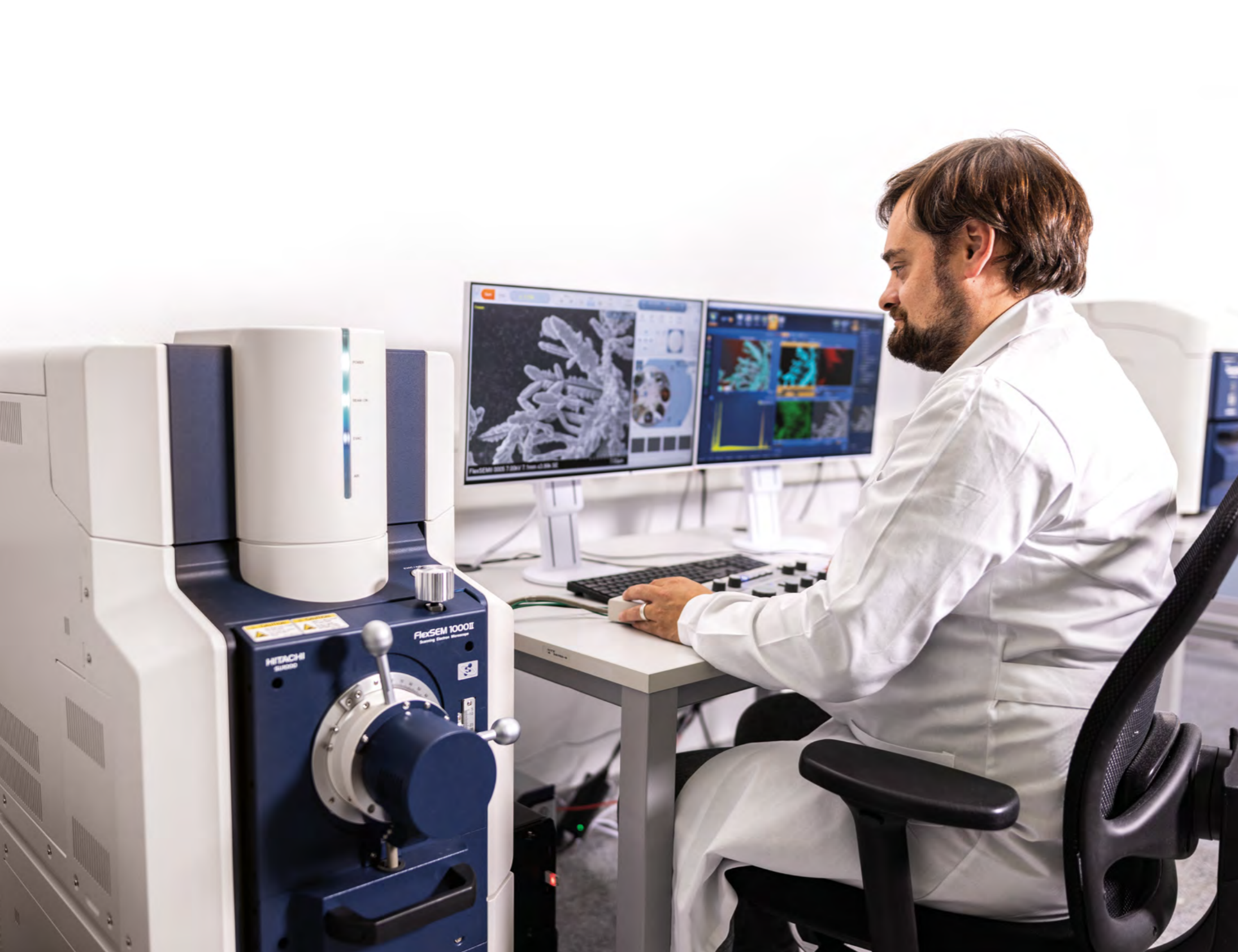


Table Top / Compact SEM

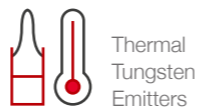


TM4000 III



FLEXSEM II





TM4000 III

SEM imaging and elemental analysis in minutes



Beyond Optical Stereo Microscopy

Designed as a logical extension of optical stereo microscopy, the TM4000 III is an entry-level device for scanning electron microscopy. It allows you to image samples in the shortest possible time with good resolution, depth of field, and contrast between different materials. All without time-consuming preparation (uncoated). If needed, you can also determine the chemical composition and element distribution. Easy navigation on the motorised X,Y sample stage is done using an automatically generated, zoomable colour photo overview. This can be supplemented locally by SEM photo snapshots.

+ Optional Accessories

EDX with sensor sizes up to 65mm²

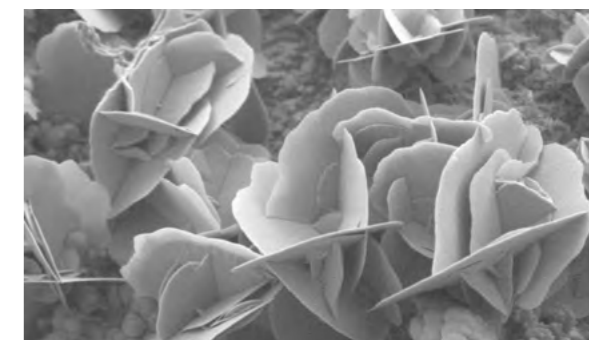
Automatic multi-range image capture ("Multi-zigzag")

Automation via Python scripting or EM Flow Creator

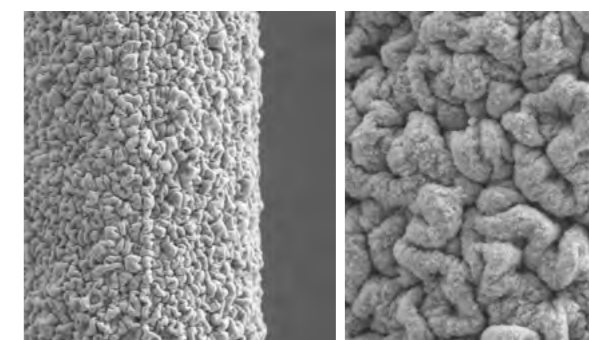
Hitachi Map 3D packages for additional functions such as 3D reconstruction, roughness measurement, particle and pore analysis, image processing, colour segmentation, etc.



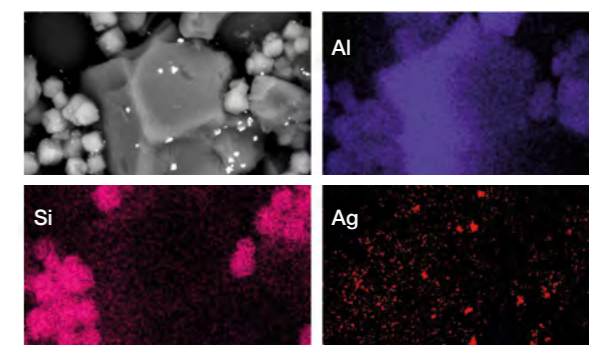
The sample stage is pulled completely out of the chamber for easy sample changes



Copper sulphide crystals. 5kV, SE signal



Corroded copper wire. 10kV, SE signal



Cosmetic powder, EDX analysis. 15kV

✓ Product Features

EDX with 30mm² or 60mm² sensor size can be fully integrated, immediate switching between observation and element analysis

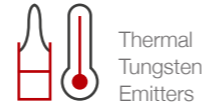
4 acceleration voltages 5 | 10 | 15 | 20kV with 5 probe current modes each

Optical colour navigation camera

3 chamber pressure stages

4-segment backscattered electron detector

Probe current reading and IFT functionality



Thermal
Tungsten
Emitters

FLEXSEM II

Full SEM functionality in a compact, intuitive design



Compact SEM with Low Vacuum Function

FlexSEM II is a table-top / compact SEM for imaging tasks that go beyond the performance of conventional table-top SEMs. It's the ideal system for anyone who doesn't want to invest in a classic SEM, but also doesn't want to compromise on imaging performance and detector variability.

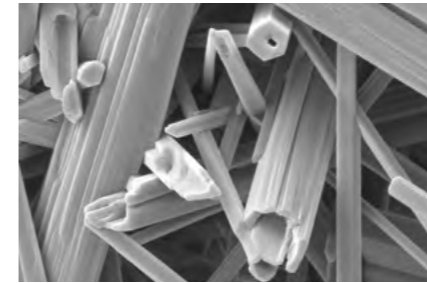
+ Optional Accessories

EDX from Bruker or Oxford Instruments can be fully integrated. Automatic particle analysis possible. Available detectors:

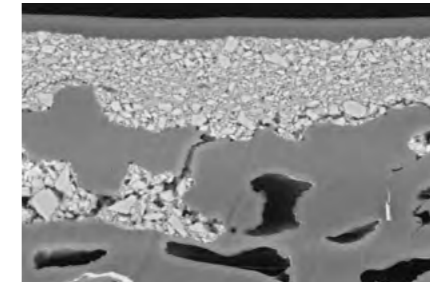
- Bruker: 30mm² or 60mm² (1 or 2 detectors)
- Oxford Instruments: 30mm² or 65mm² (1 detector)

Hitachi Map 3D packages for additional functions such as 3D reconstruction, roughness measurement, particle analysis, image processing, and colour segmentation.

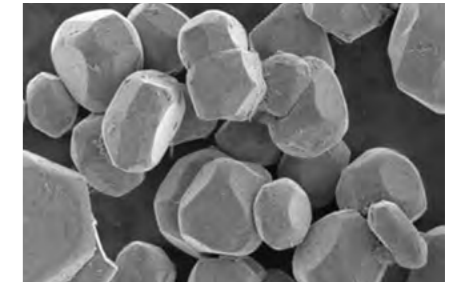
FLEXSEM II



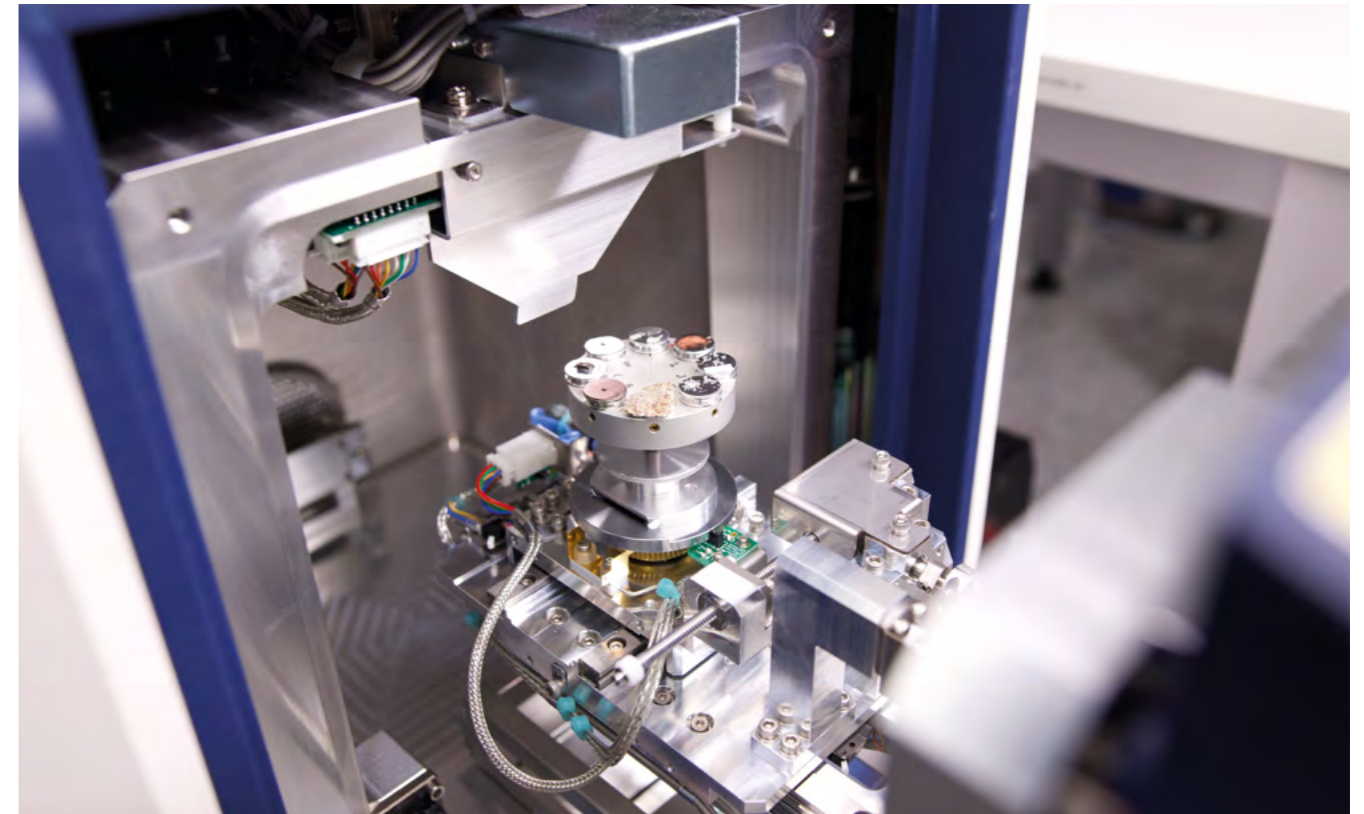
Pharmaceuticals. 4.0 kV, magnification 7,500x



Paper. 10.0 kV, magnification 2,700x



Phosphor. 1.5 kV, magnification 5,000x



Eucentric 5-axis specimen stage

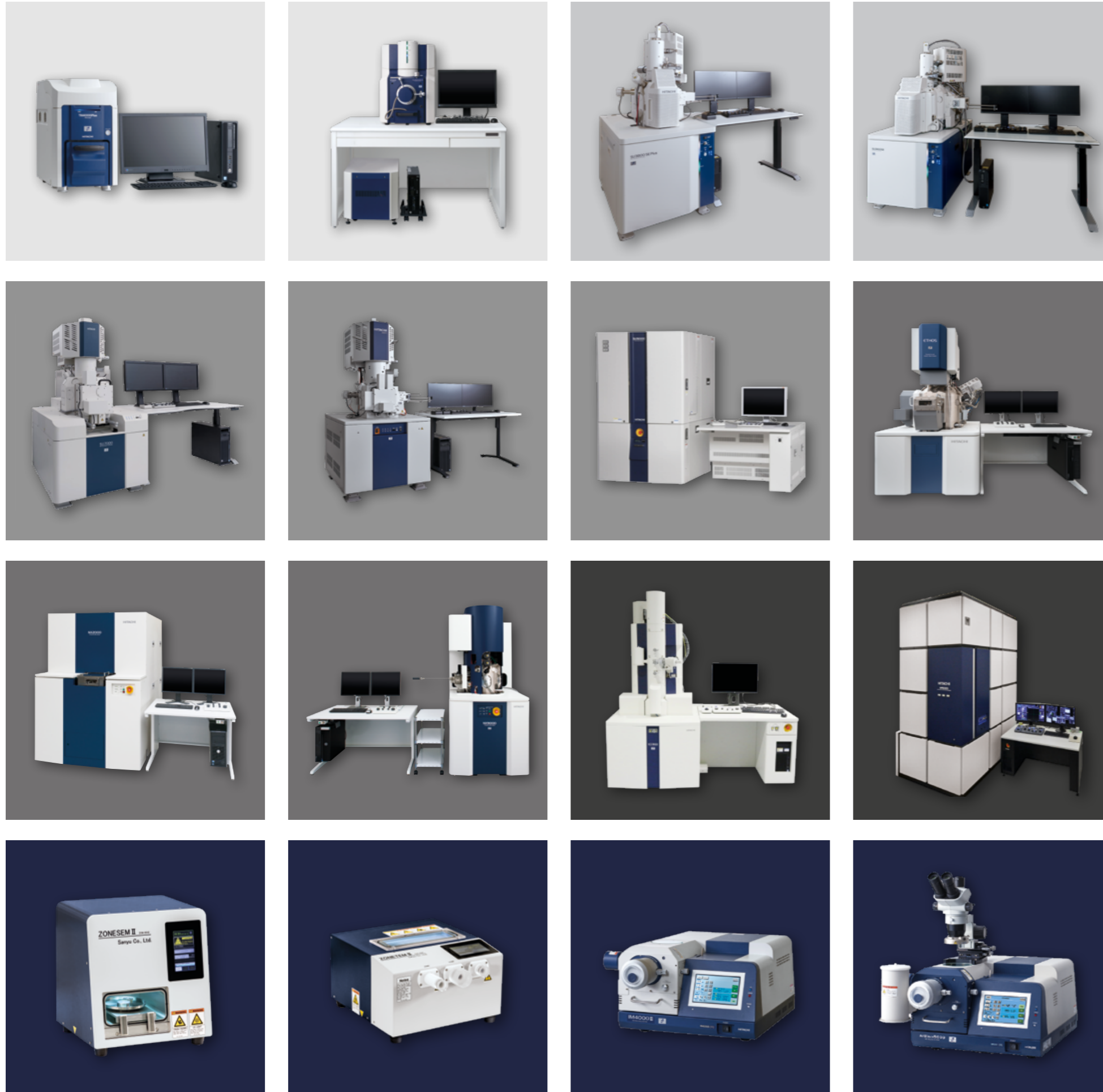
✓ Product Features

4nm @ 20kV
High-resolution electron optics with beam energies between 300eV and 20keV

High and adjustable low vacuum up to 100Pa

SE and 4+1 segment backscatter detector standard, low vacuum SE optional (UVD); can also be used for cathodoluminescence and STEM imaging, optical colour navigation camera and chamberscope

5-axis sample stage for samples up to max. 153mm diameter and 40mm height



**Not sure which
product aligns
with your needs?**

Our experts are here to
provide guidance and help
you make the best choice.



Follow us

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Notice: For correct operation, follow the instruction manual when using the instrument.

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